

QUICKVIEW 450



Process Monitoring and Quality Assurance System

	Travel	mm
QuickView 450	X axis	450
	Y axis	450
	Z axis	150
Extended Y (optional)	Y axis	610

High Performance Large Travel Non-Contact Metrology System

The **QuickView 450** video measurement system is designed with throughput in mind. High speed linear motor drives move quickly and precisely. The dual magnification optical system provides near instantaneous magnification changes - helpful when locating small features. QuickView 450 is excellent for electronic and semiconductor applications where numerous distances and dimensions must be measured rapidly.

QuickView 450 offers:

- 0.1 μm XYZ resolution (0.04 μm optional in XY, 0.05 μm optional in Z)
- High-speed XY linear motor drive system (up to 400 mm/sec)
- Programmable Ring Light (PRL) with multi-color LEDs for optimal edge detection
- Multisensor measurement capability with optional touch probe, through-the-lens (TTL) laser, and Rainbow Probe™ scanning white light sensor



■ Standard ■ Optional

- **Stage travel (XYZ):** 450 x 450 x 150 mm
- **Extended Y axis:** 610 mm
- **Measuring unit dimensions (approx LWH):** 146 x 102 x 193 cm, 1000 kg
- **Crated dimensions/weight:** Contact OGP for crated size/weight
- **XYZ scale resolution:** 0.1 μm
- **XY scale resolution:** 0.04 μm
- **Z scale resolution:** 0.05 μm
- **Motor drives:** Linear motor (XY), DC servo (Z), with joystick control
- **Maximum stage speed:** 400 mm/sec (X,Y), 100 mm/sec (Z)
- **Maximum stage acceleration:** 1000 mm/sec² (X,Y), 200 mm/sec² (Z)
- **Worktable:** Hardened, with fixture holes and removable stage glass, 75 kg load capacity

- **Optics:** Fixed lens, dual magnification system, with standard 2.5x lens. All other lenses are optional.

Objective Magnification	0.8x/3.2x	1x/4x	2.5x/10x	5x/20x	10x/40x	25x/100x
Working Distance:	110 mm	34 mm	34 mm	33 mm	20 mm	13 mm
Field of View Low ■	7.4 x 5.7	6.1 x 4.8	2.4 x 1.9	1.2 x 0.9	0.6 x 0.5	0.25 x 0.19
(mm) Low ■	10.1 x 7.9	8.4 x 6.6	3.4 x 2.6	1.7 x 1.3	0.8 x 0.7	0.34 x 0.26
High ■	1.84 x 1.43	1.53 x 1.2	0.61 x 0.48	0.31 x 0.24	0.15 x 0.12	0.06 x 0.05

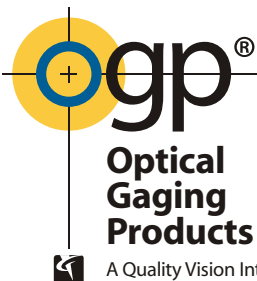
- **Optical accessory:** Grid projector
- **Cameras:** Dual high resolution B&W CCD with 765 x 576 pixel arrays; 4:1 ratio
- **Cameras:** Dual high resolution B&W CCD with 765 x 576 pixel arrays; 6:1 ratio
- **Illumination:** LED substage, LED coaxial TTL surface, multi-color (red, blue, green, and composed white) LED Programmable Ring Light (PRL)
- **VectorLight™ LED ring light** (in lieu of LED Programmable Ring Light)
- **Image processing:** 256 level grayscale processing with 10:1 to 50:1 sub-pixeling
- **Multisensor options:** Touch probe and change rack, on-axis TTL laser, Rainbow Probe™ scanning white light sensor (contact OGP for possible combinations of sensors)
- **Metrology software:** MeasureMind® 3D MultiSensor
- **Software:** MeasureFit® Plus, SmartReport® powered by QC-Calc™, SmartFit® 3D, MeasureMenu™, Scan-X®, SmartScript®, SmartTree™, SmartProfile™
- **Computer:** Embedded; minimum configuration Dual Core processor @ 1.8 GHz, 1 GB RAM, 80 GB hard drive, 1.44 MB floppy drive, DVD-RW drive, parallel, serial, and USB 2.0 ports, on board 10/100 LAN
- **Operating system:** Microsoft® Windows™ XP Professional
- **Computer accessories:** Integrated, adjustable operator workstation arm (to support computer peripherals); single or dual 22" flat panel LCD monitor(s), keyboard, three button mouse (or user supplied)

- **XY area accuracy:** $E_z = (1.5 + 5L/1000) \mu\text{m}^*$
- **Z linear accuracy:** $E_z = (1.5 + 5L/1000) \mu\text{m}^*$
- **Z linear accuracy:** $E_z = (1.0 + 5L/1000) \mu\text{m}^*$ (with optional TTL laser and 5x lens or higher, or TP200 touch probe)

- **Power requirements:** 115/230 vac, 50/60 Hz, 1 φ, 1000 W
- **Rated environment:** Temperature between 18 and 22° C, stable to ± 1° C; 30-80% humidity (non-condensing); vibration <0.001g below 15 Hz
- **Operating environment:** 15-30° C

- **Warranty:** One year
- **Accessories:** Fixtures and calibration artifacts, rotary indexers

*Where L=measuring length in mm. Applies to thermally stable system in rated environment, high magnification with 2.5x lens unless otherwise noted, and evenly distributed 5 kg load. Depending on load distribution, accuracy at maximum rated load may be less than standard accuracy. XY axis artifact: QVI grid reticle at standard measuring plane. Z axis artifact: QVI step gage or master gage blocks.



Multisensor Measurements for Manufacturing Professionals

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